



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application Serial No. ....09/927,230  
Confirmation No.....6111  
Filing Date .....August 9, 2001  
Inventor.....Trung Tri Doan  
Assignee .....Micron Technology, Inc.  
Group Art Unit.....1722  
Examiner .....R. Kunemund  
Customer No.....021567  
Attorney's Docket No. ....MI22-1372  
Title:..... Variable Temperature Deposition Methods

**SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT**

Reference -See Attached Form PTO-1449

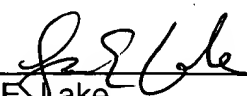
In compliance with 37 C.F.R. §§ 1.56, 1.97 and 1.98, your attention is directed to the United States patents and other references listed on the attached Form PTO-1449. No admission is made regarding whether all the submitted references are prior art.

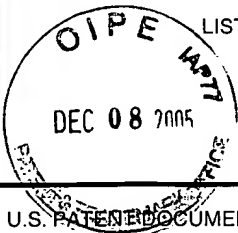
This Supplemental Information Disclosure Statement is being filed after the filing of the Request for Continued Examination (RCE) Application and before receipt of the first Office Action. Therefore, no fee is believed to be required. However, in the event that a fee is required for filing this Supplemental Information Disclosure Statement, please charge the fee specified under 37 C.F.R. §1.17(p) to Deposit Account No. 23-0925. Please credit Deposit Account No. 23-0925 with any overpayment of the above fee.

Citation of these references is respectfully requested.

Respectfully submitted,

Dated: 08 Dec 2005

By:   
James E. Lake  
Reg. No. 44,854

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-1372	SERIAL NO. 09/927,230			
 <p>LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)</p>				APPLICANT: Trung Tri Doan				
				FILING DATE August 9, 2001	GROUP 1722			
<b>U.S. PATENT DOCUMENTS</b>								
*Examiner's Initials		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
	AA	6,165,916	12/2000	Muraoka et al.				
	AB							
	AC	2005/0124171 A1	06/2005	Vaartstra				
	AD	2005/0124158 A1	06/2005	Lopatin et al.				
	AE	2005/0124153 A1	06/2005	Cohen, Uri				
	AF	2005/0101119 A1	05/2005	Li et al.				
	AG							
	AH							
	AI							
<b>FOREIGN PATENT DOCUMENTS</b>								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AJ							
	AK							
	AL							
<b>OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)</b>								
	AM							
	AN							
	AO							
EXAMINER		DATE CONSIDERED						
<p>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</p>								